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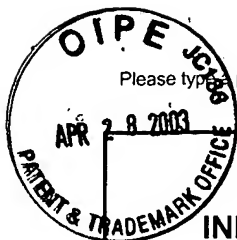
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (use as many sheets as necessary)				<b>Application Number</b>	10/047,976
				<b>Filing Date</b>	1/13/02
				<b>First Named Inventor</b>	Steven Teig
				<b>Group Art Unit</b>	2825
				<b>Examiner Name</b>	
<b>Sheet</b>	1	of	1	<b>Attorney Docket Number</b>	SPLX.P0084

U.S. PATENT DOCUMENTS						
Examiner* Initials	Cite No.	U.S. Patent Document Number Kind Code* (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
VS	1.	2001/ 0003843	A1 Scepanovic et al.	06-14-01		
	2.	4,615,011	Linsker	09-30-86		
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	24.	5,859,449	Kobayashi et al.	01-12-99		
VS	25.	5,898,597	Scepanovic et al.	04-27-99		

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Sheet	2	of	2	Attorney Docket Number	SPLX.P0084

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VS	52.	6,516,455	B1	Teig et al.	02-04-03	

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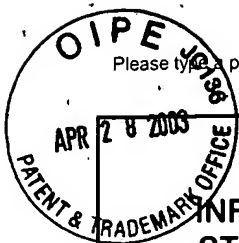
U.S. PATENT DOCUMENTS						
VS	53.	6,516,455	B1	Teig et al.	02-04-03	<input checked="" type="checkbox"/>
VS	54.	2003/0025 205	A1	Shively	02-06-03	<input checked="" type="checkbox"/>

FOREIGN PATENT DOCUMENTS								
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		Office <sup>3</sup>	Number <sup>4</sup>	Kind Code (if known) <sup>5</sup>				
VS	55.	JP	64-15947		Ouchi	01-19-89	<input checked="" type="checkbox"/>	
VS	56.	JP	04000677		Fujiwara et al.	01-1992	<input checked="" type="checkbox"/>	

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				Group Art Unit	2835
				Examiner Name	
Sheet	4	of	4	Attorney Docket Number	SPLX.P0084

### OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Examiner* Initials	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>6</sup>
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